

In Situ Time-Resolved Diffraction with High Energy X-rays from Metal Oxides: Rietveld Refinements

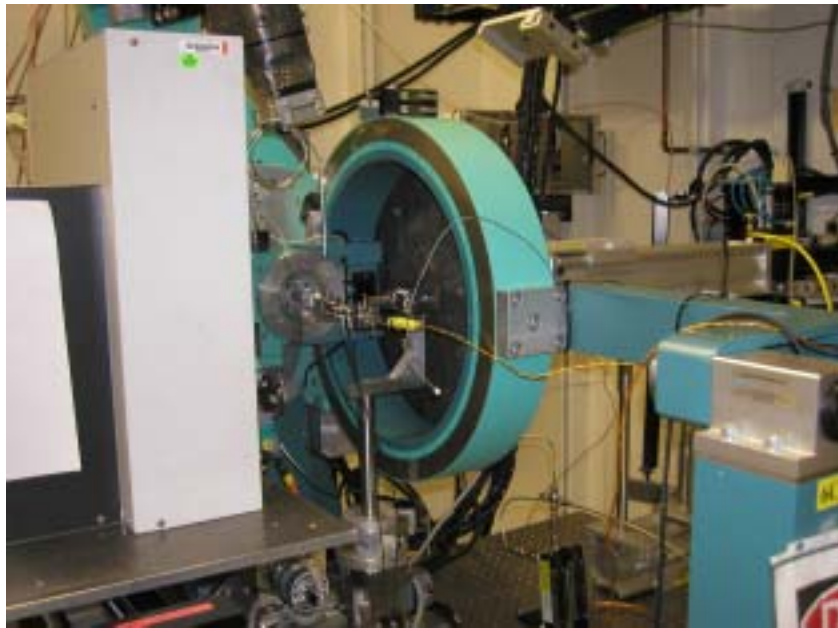
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Jose Rodriguez, Chemistry, BNL,
Peter Lee, APS, ANL
Peter Chupas, Materials Science, ANL

Outline

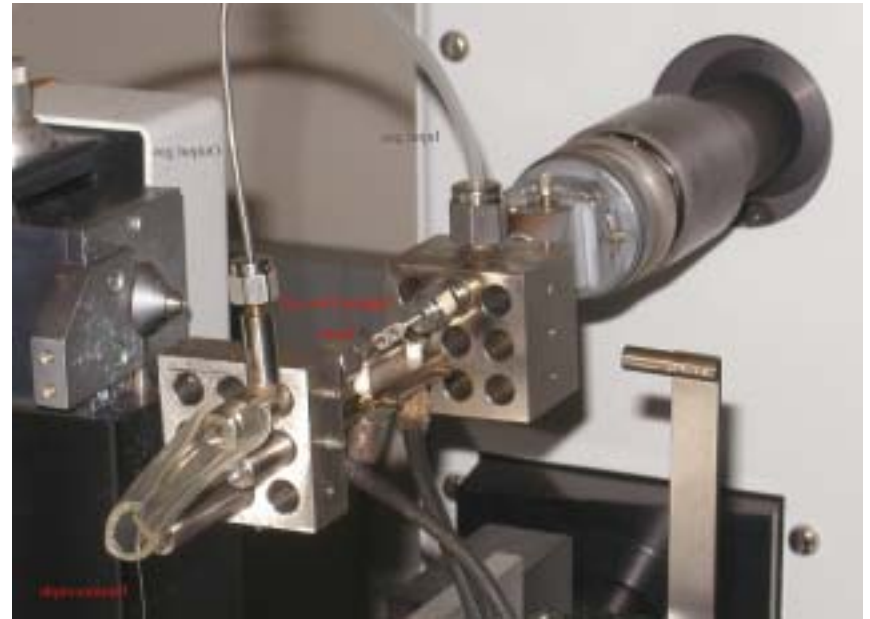
- Motivation: Structural models of intermediates during catalytic processes
- Technique: In situ Time-resolved XRD
- Applications
 - NiO reduction
 - CuO/Cu₂O/Cu reduction
 - Ceria reduction

Setup for In situ Data Collection

Mar345 Image Plate
Detector / Goniometer



Flow Cell

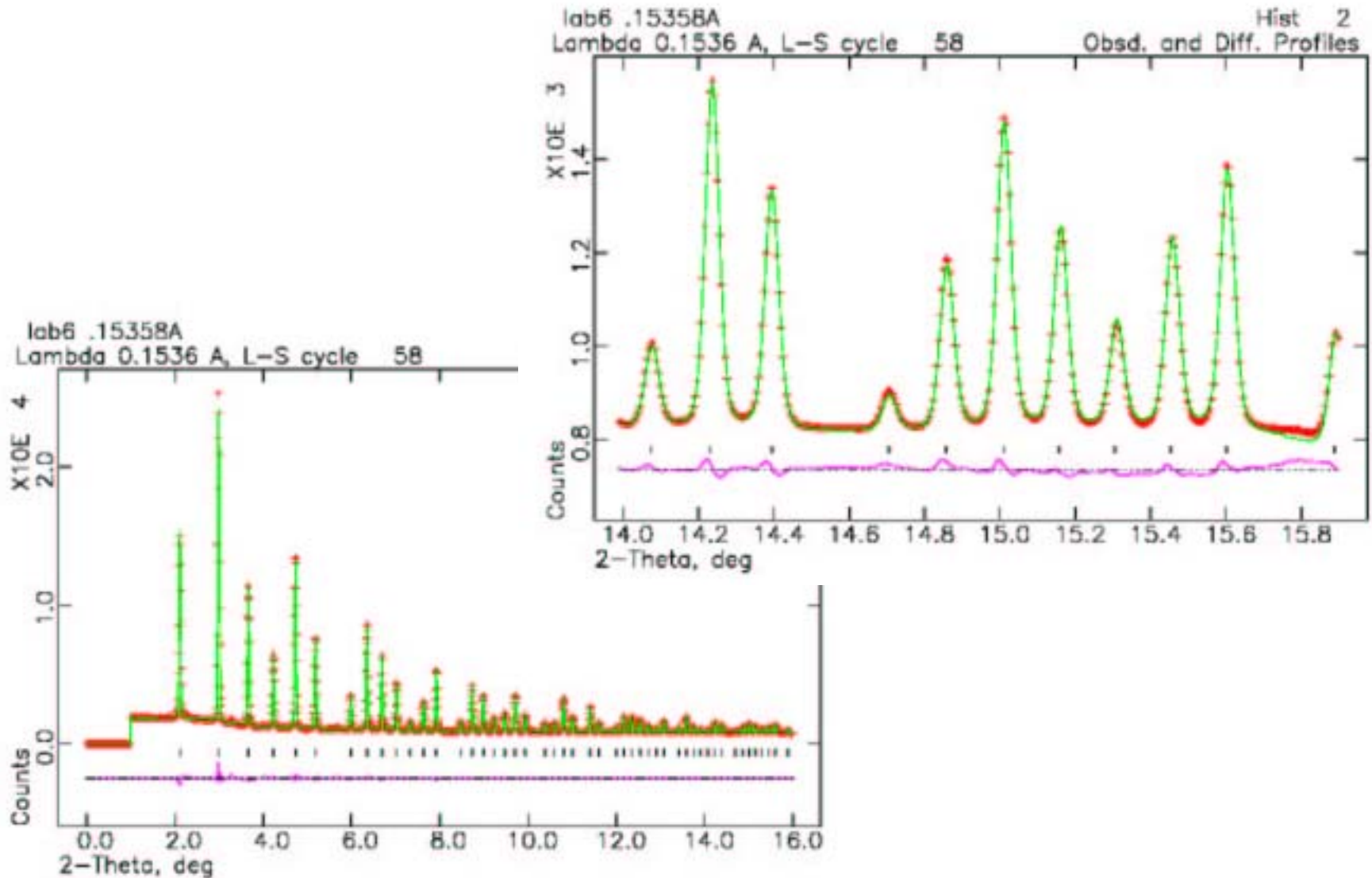


T: 25-950°C P: .001- 120 atm Time: Current=2min/Future 0.1sec

Advantages of Diffraction with High Energy (80-100Kev)

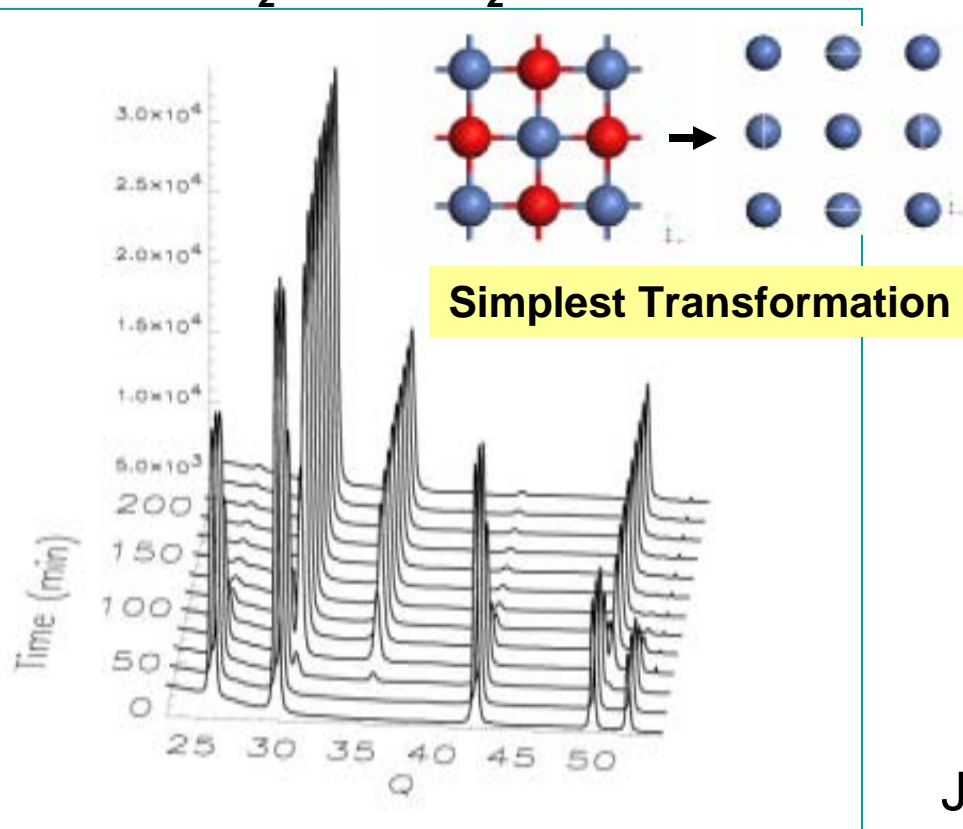
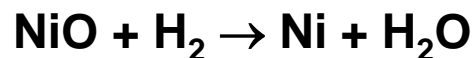
- Low absorption:
 - Corrections negligible
 - Bulk vs. surface properties
 - More penetration of *in situ* cell
- High Q resolution
 - Improved over-determination
 - Reduce U / occupancy correlation

Sharp lines from standard LaB_6

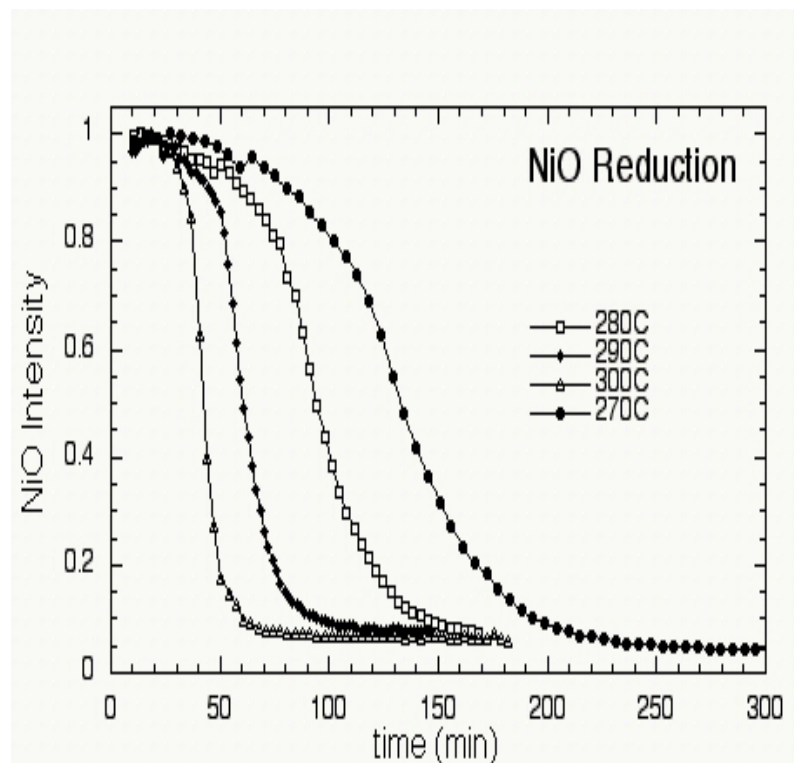


Kinetics NiO Reduction From TR XRD

Isothermal TR-XRD at 280°C



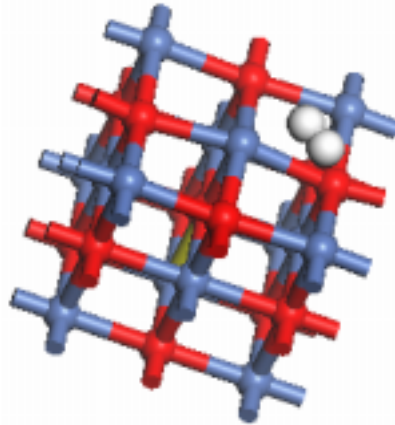
111 intensity during reduction at four temperatures.



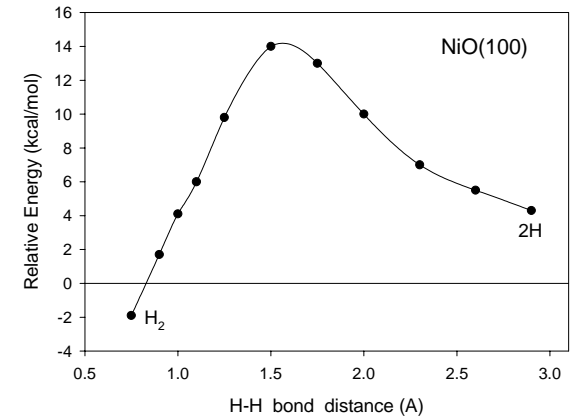
J. Am. Chem. Soc. **124**,346-354 (2002)

DF Calculations H_2 Interactions with NiO

H_2 on smooth NiO
Weak adsorption
16Kcal/mol barrier
Endothermic

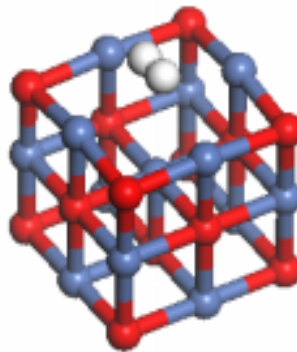


**E
N
E
R
G
Y**

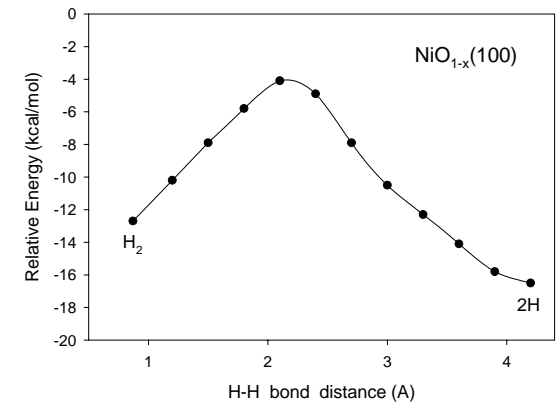


H-H Distance

H_2 on NiO defect
Strong adsorption
8 Kcal/mol barrier
Exothermic



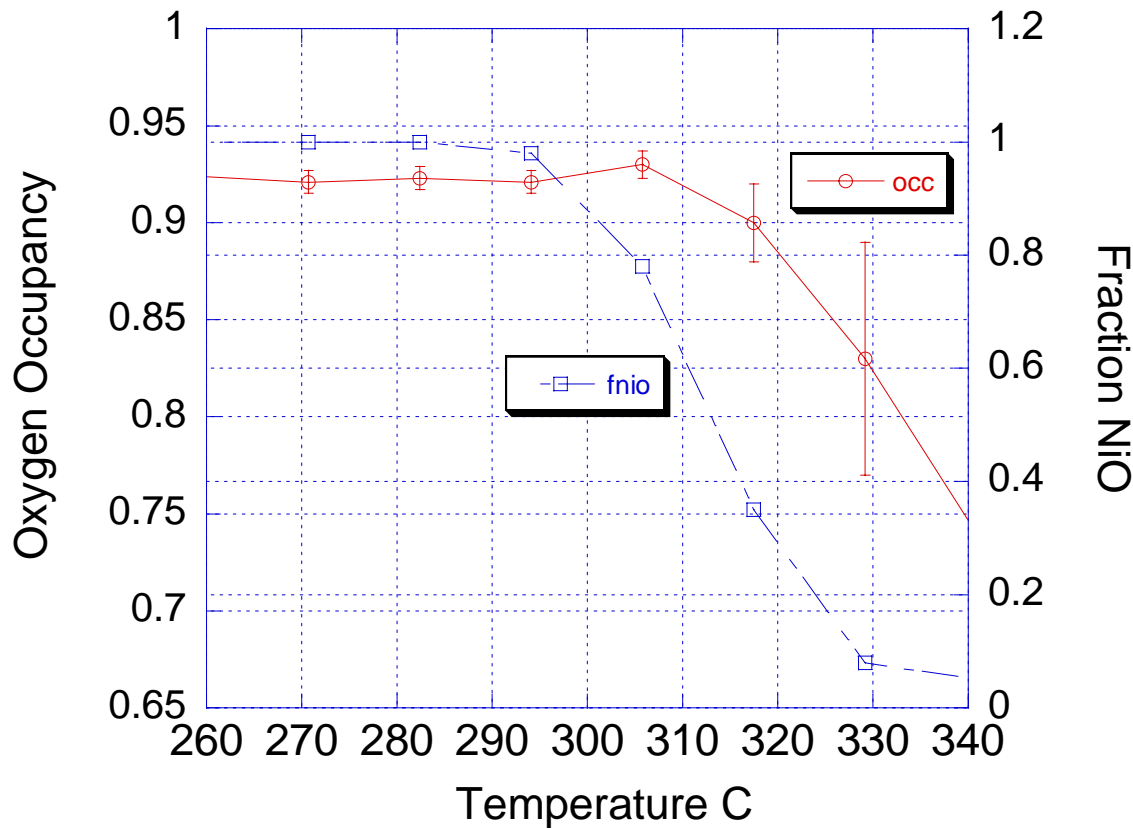
**E
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Y**



Challenge

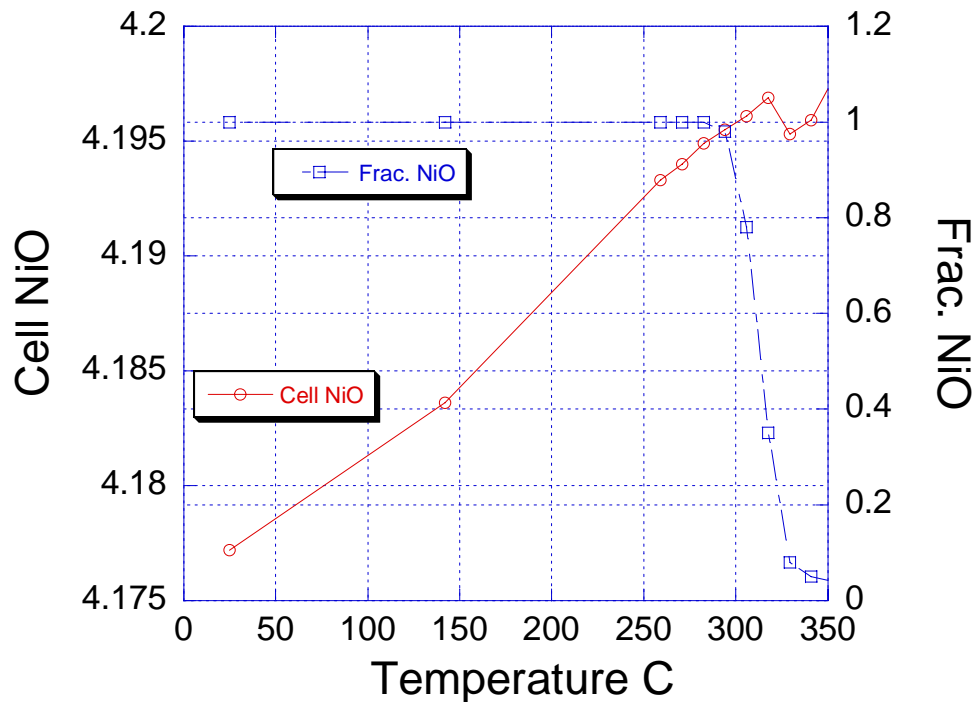
- Can refinement of high Q powder data give information about oxygen vacancy and interstitial oxygen formation?
- Can structural information can be obtained?

Ramp NiO in 5%H₂/He



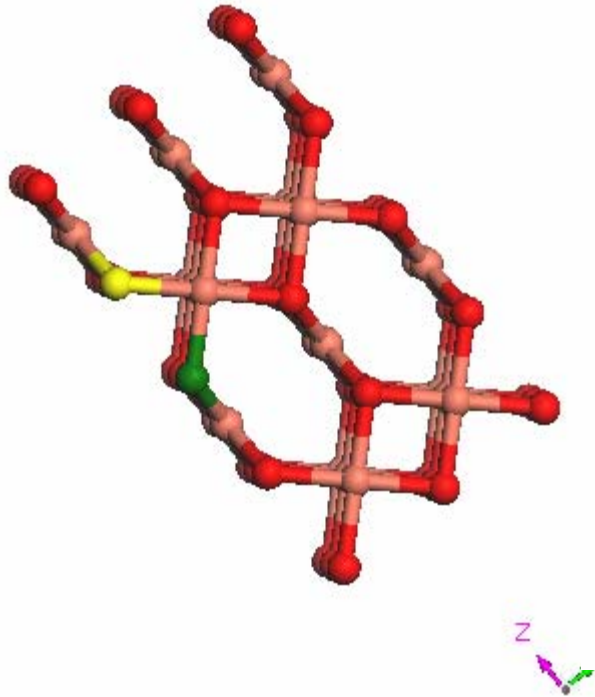
1. Fraction NiO decreases faster than oxygen occupancy
2. Occupancies of oxygen are constant, but slightly low until NiO fraction is less than 0.5

Ramp NiO in 5%H₂/He



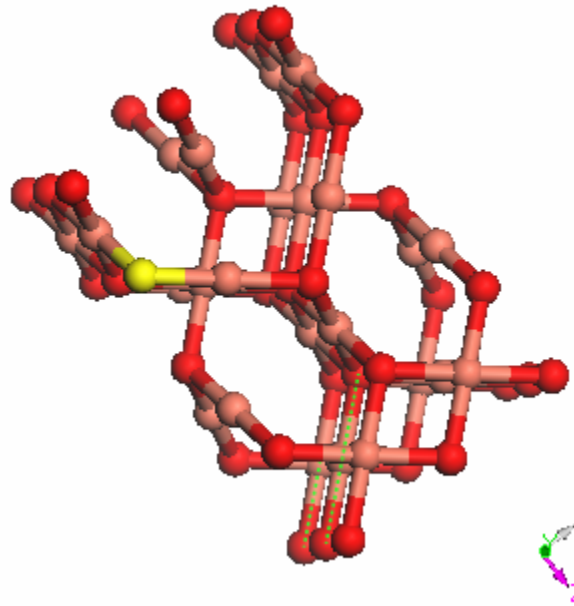
Cell continues to expand until NiO fraction less than 0.4 and then it contracts slightly

3 Oxides of Copper related to tetragonal cell show common features/O changes

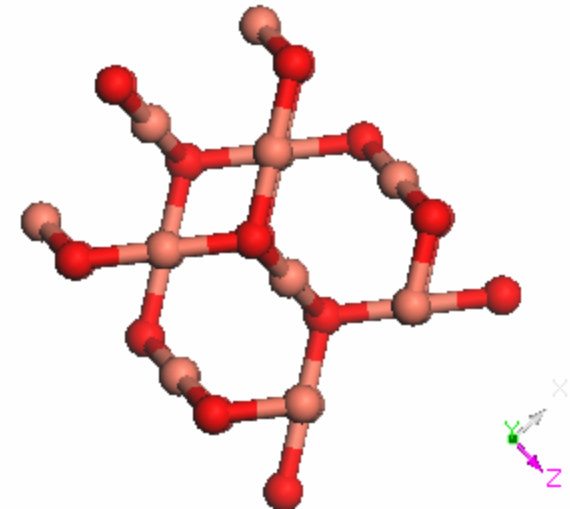


CuO

- O



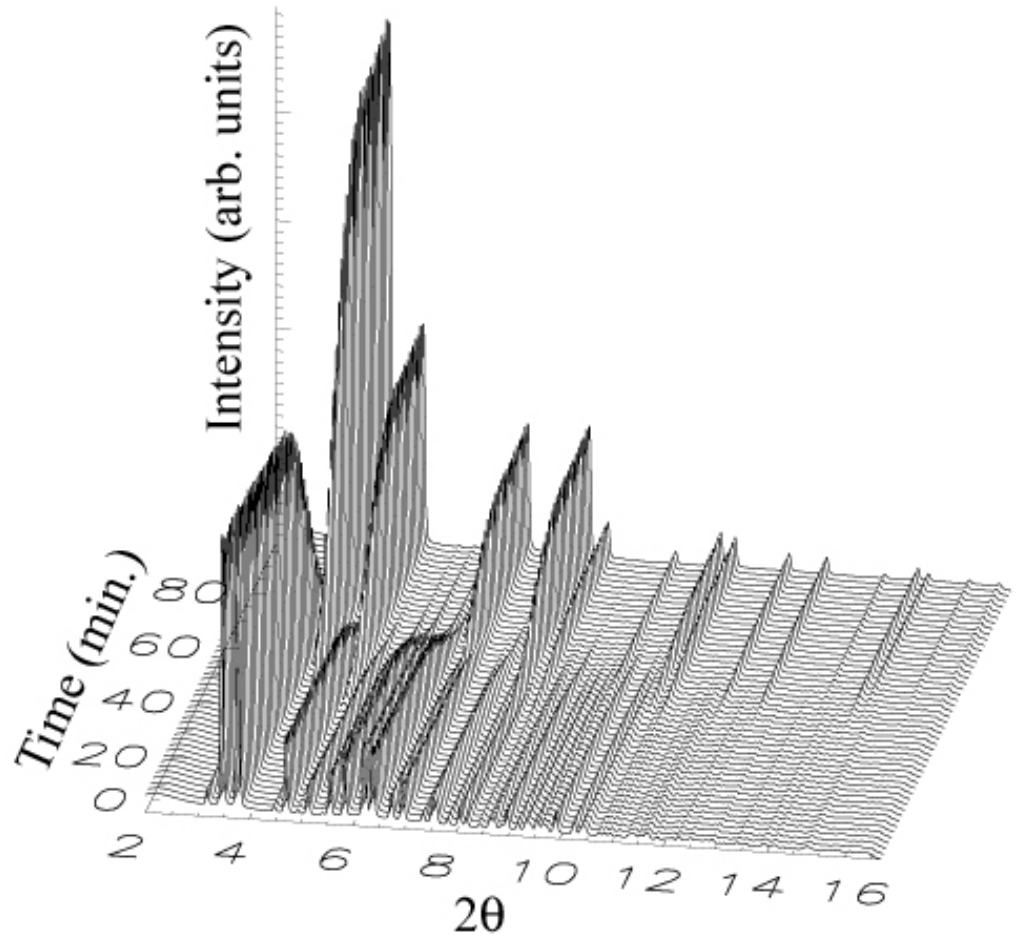
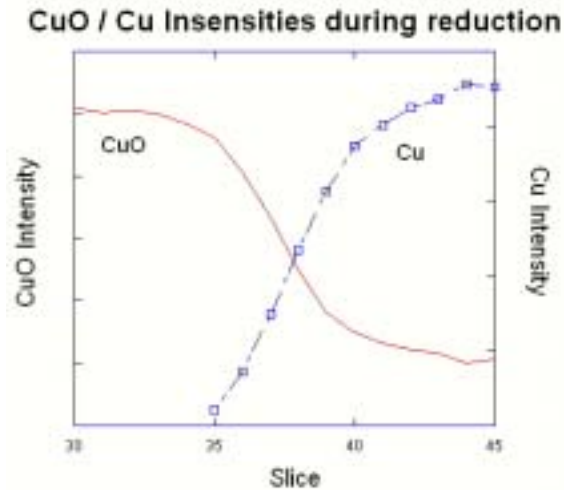
Cu_4O_3



Cu_2O

- O

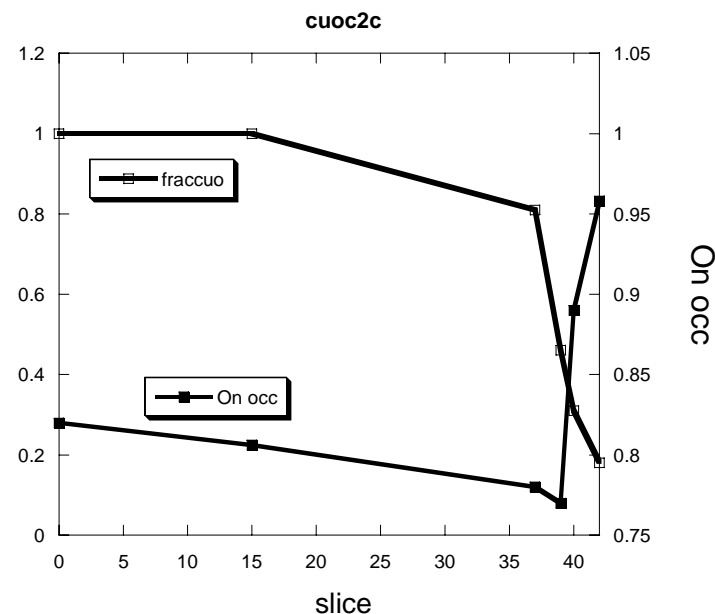
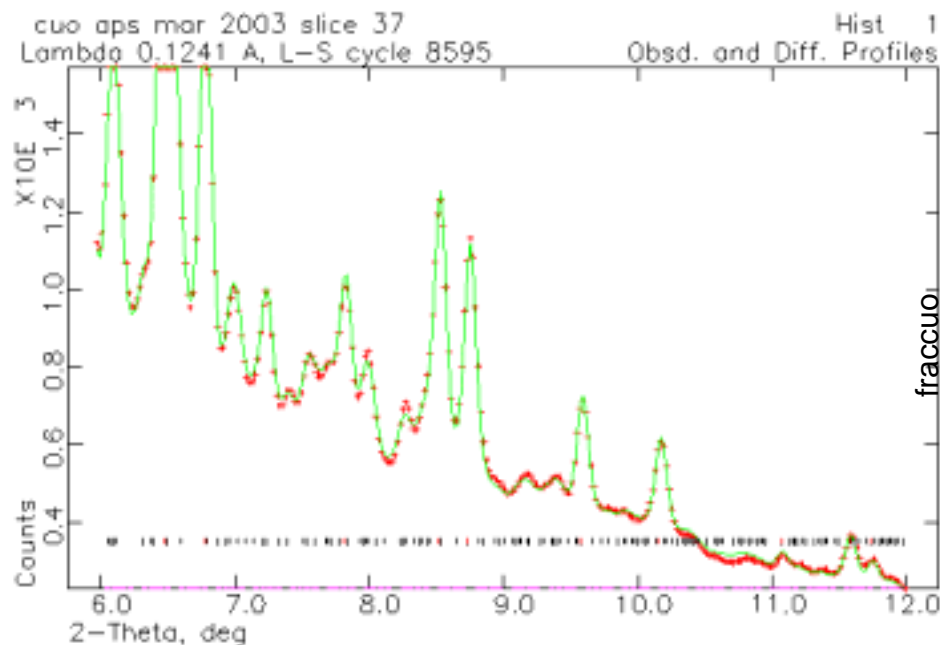
Time resolved diffraction pattern



No diffraction from
Intermediate phases
Is there any information
In the TR intensity data
of CuO phase?

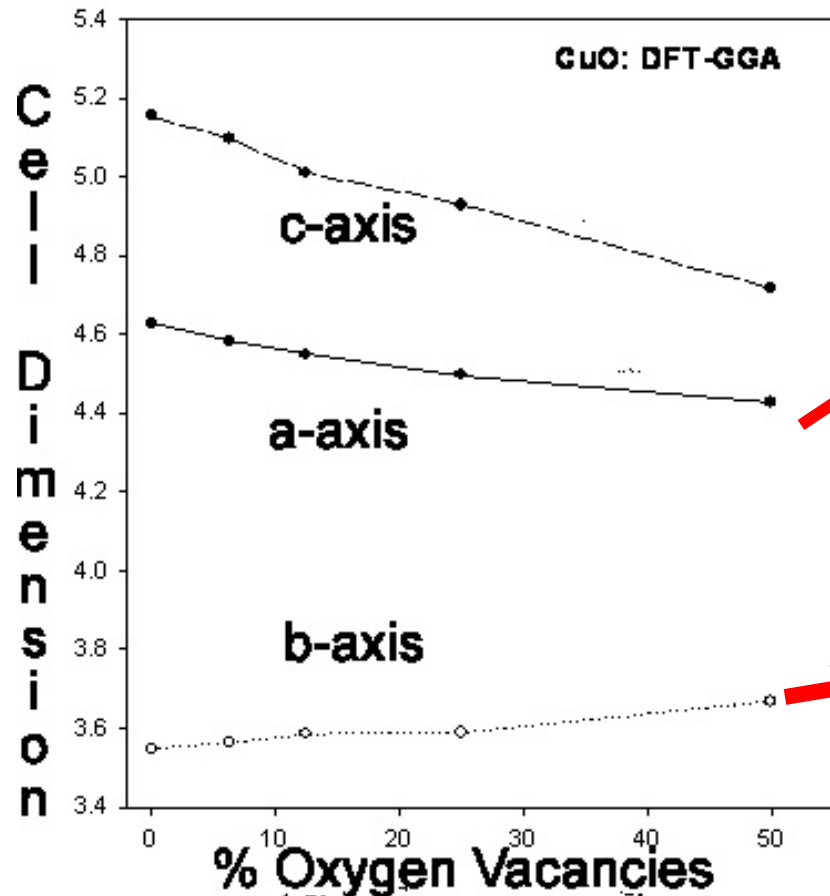
Can you refine O occupancies when small weight fraction?

Current approach fails at weight fraction < 0.46

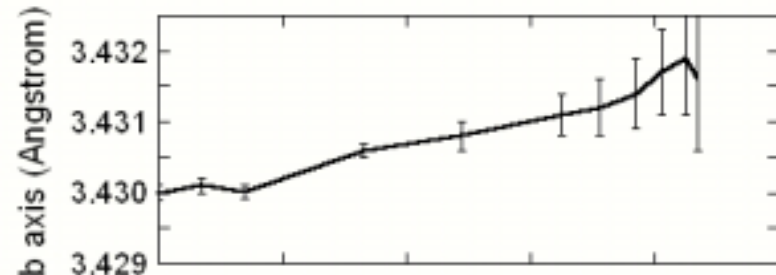
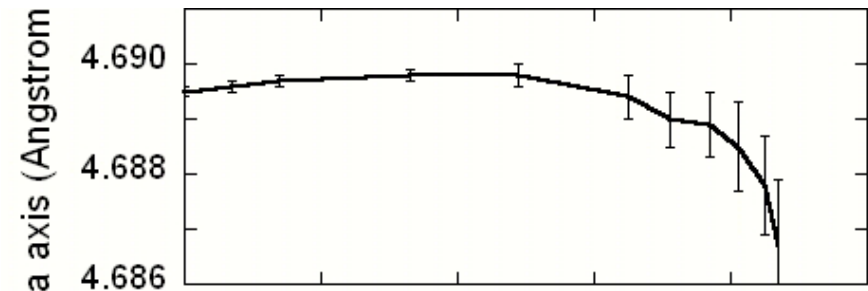


Observed and Calculated Effect of Oxygen Vacancies on Cell Dimensions

calculated



X-ray



Wt Fraction Cu

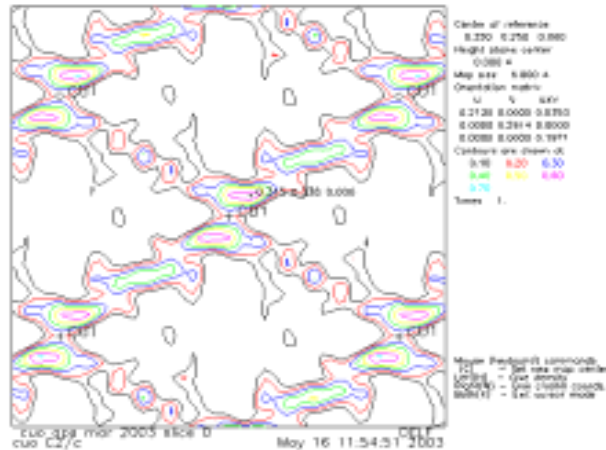
Gsas refinement of initial CuO

Thermal	O occ	R(F ²)	χ^2
Aniso Cu	0.820(6)	0.029	0.37
aniso Cu	1.0(fix)	0.036	0.62
Iso Cu	0.828(6)	0.034	0.50
Iso Cu	1.0(fix)	0.039	0.84

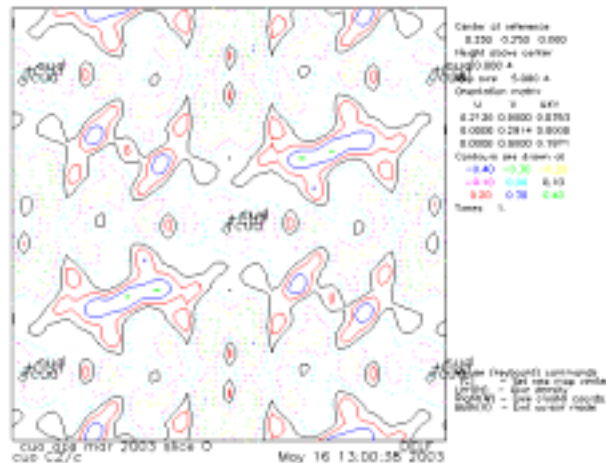
O Occupancy significant, but not full
Cu anisotropic motion significant

Cu disorder

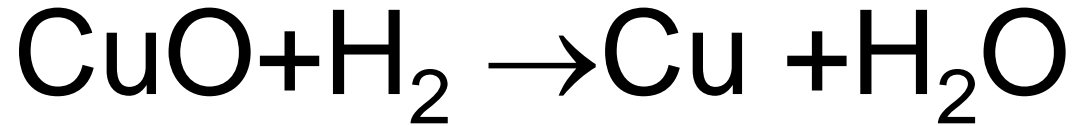
High Q data important to resolve peaks



Cu on 1bar



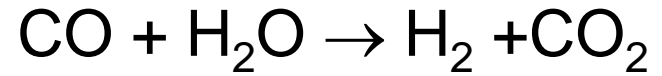
Cu .08A from 1bar



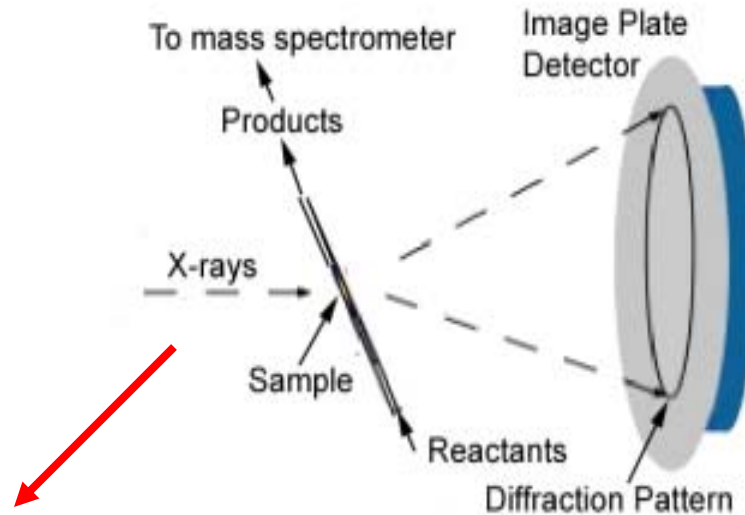
- Oxygen occupancy change in CuO small until material more than 50% gone
- CuO Cell dimension changes
 - Consistent with H imbedding initially
 - Oxygen vacancies at end
- High Q data reveals Cu disorder

Water Gas Shift Reaction:

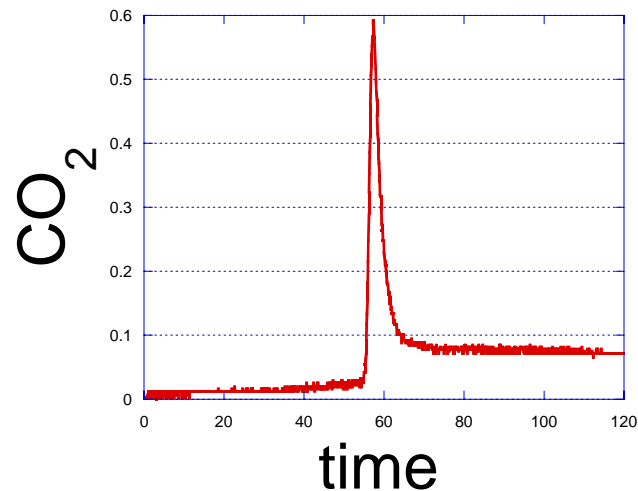
Simultaneous Measurement



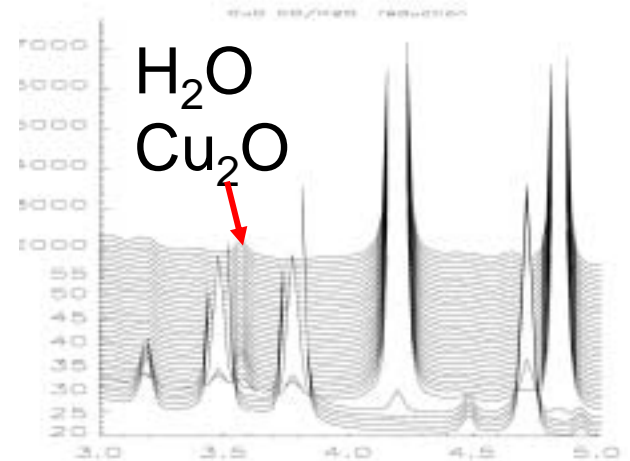
Mass Spectrum



Diffraction Pattern

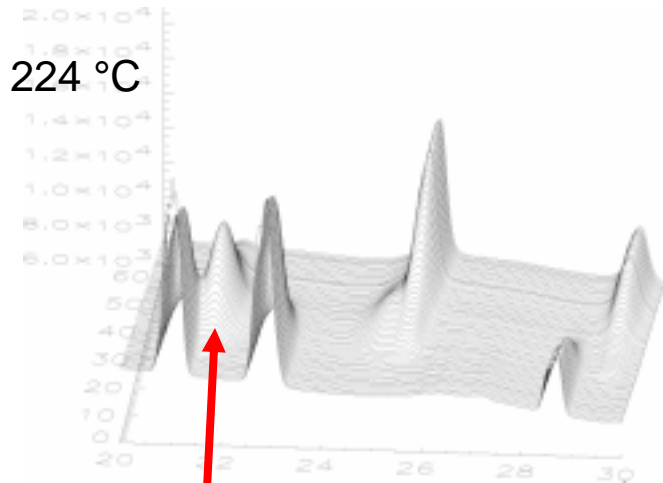


Cu_2O diffraction line observed during catalytic formation of CO_2



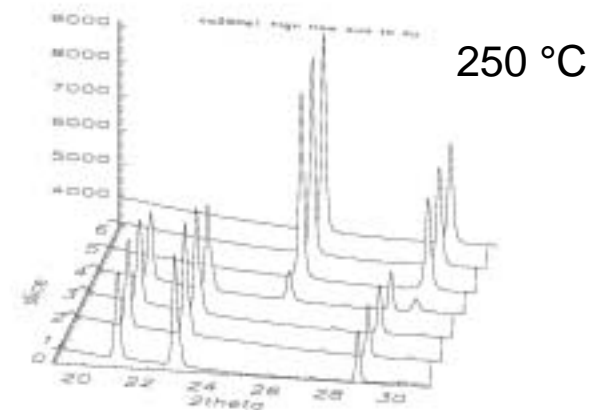
Formation of Cu_2O intermediate.

Isothermal reduction with CO



lower flow

Equilibrium Cu_2O phase forms at lower flow



High flow

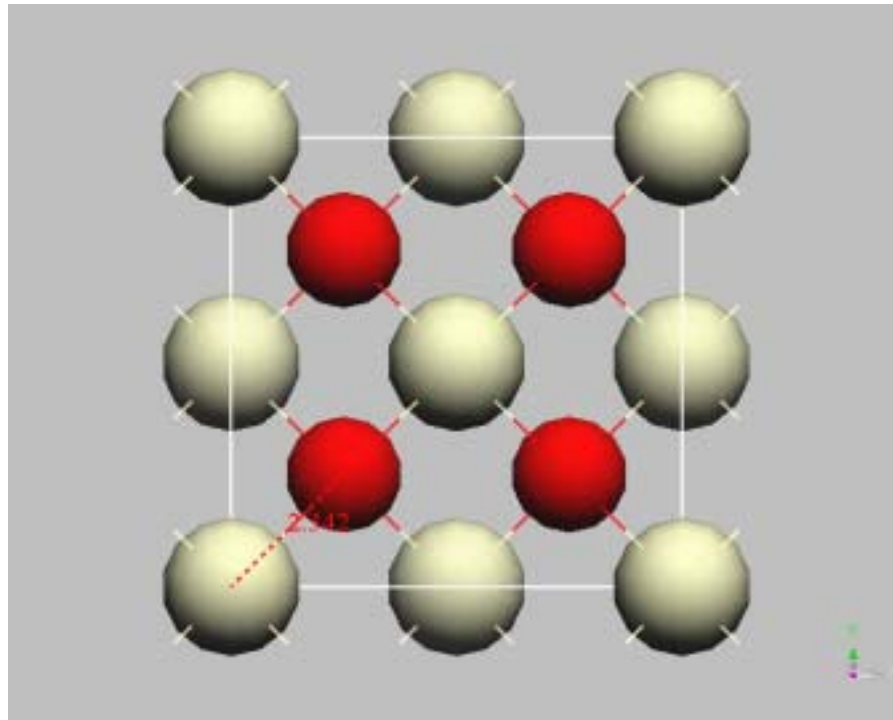
- Meta stable $\text{CuO} \rightarrow \text{Cu}$ before Cu_2O forms in high flow

Refinement shows possible disordered Oxygen in Cu_2O

Wang X, et al J Phys. Chem. (in press)

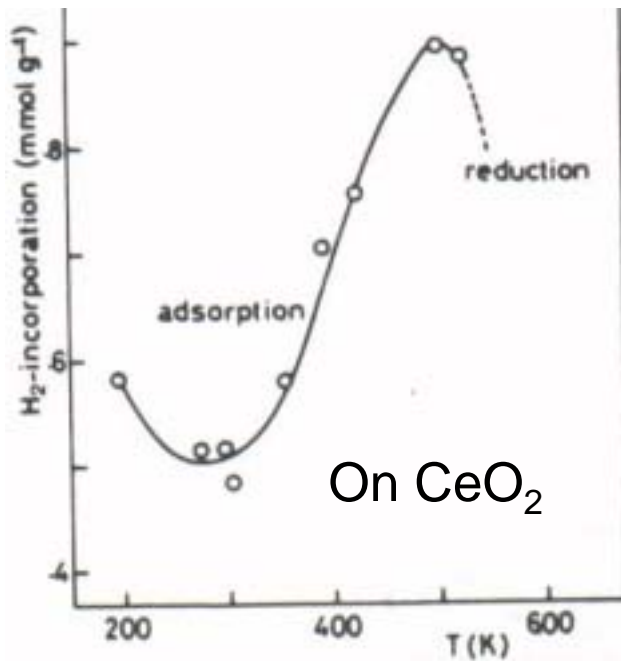
CeO₂

- Important “Oxygen” modulator in catalyst
- Reversible H₂ or CO reduction (<1000C) results in cell expansion but no phase transition.



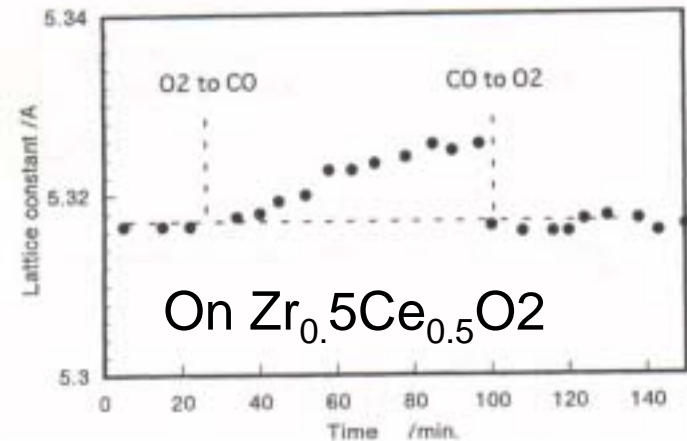
Previous Experiments Binding H₂ or CO

Fierro, et al **JSSC** (1987)



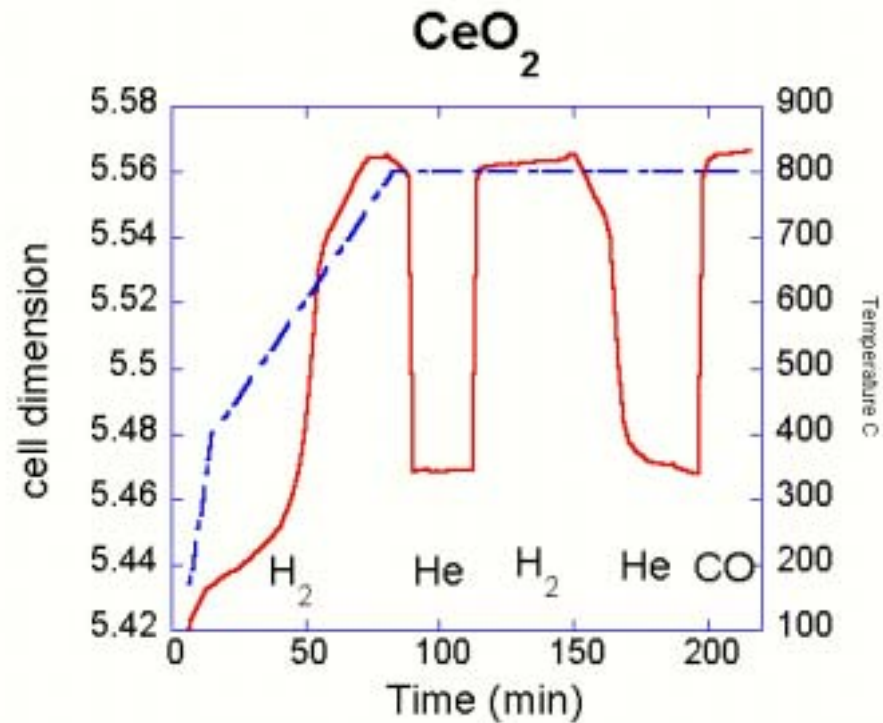
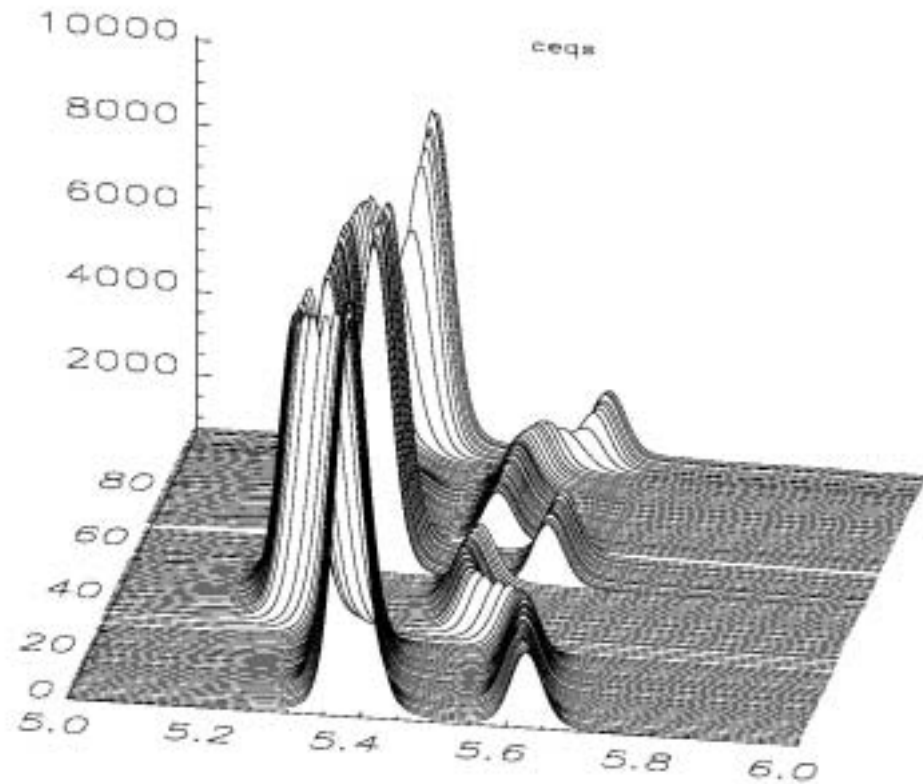
Microgravimetric measurement
Activated process
Reduction above 573°K

Ozawa & Long **Cat.Today** (1999)



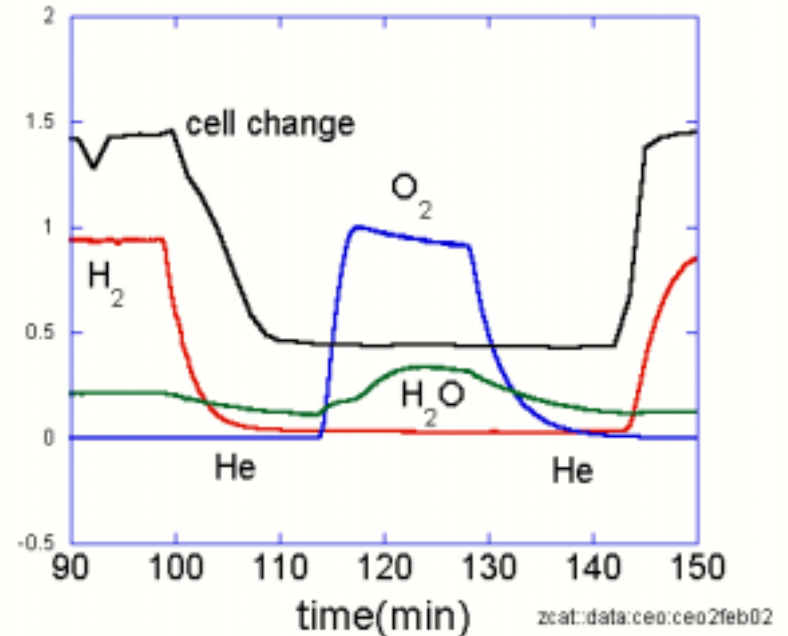
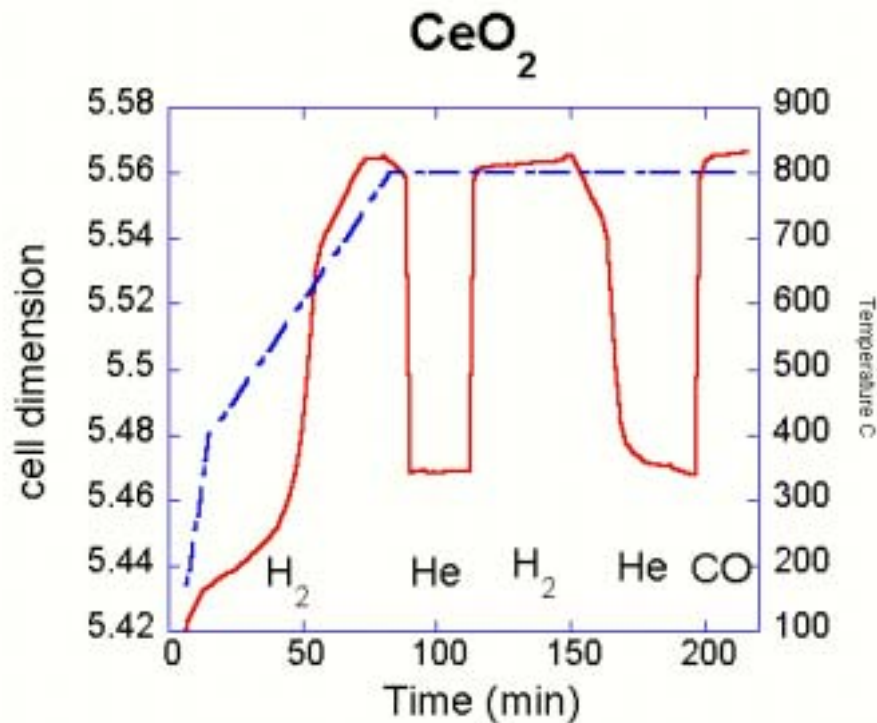
In situ X-ray diffraction at 600°C
Reversible “process”
Small cell dimension change

In situ oxidation/reduction of bulk ceria



Cell Expansion In H_2 and CO

Simultaneous gas concentrations and cell dimension changes



- Anomalous cell expansion during heating
- Cell contraction in He
- Cell expansion in CO too

Refinement of Bulk CeO₂ In Situ Data

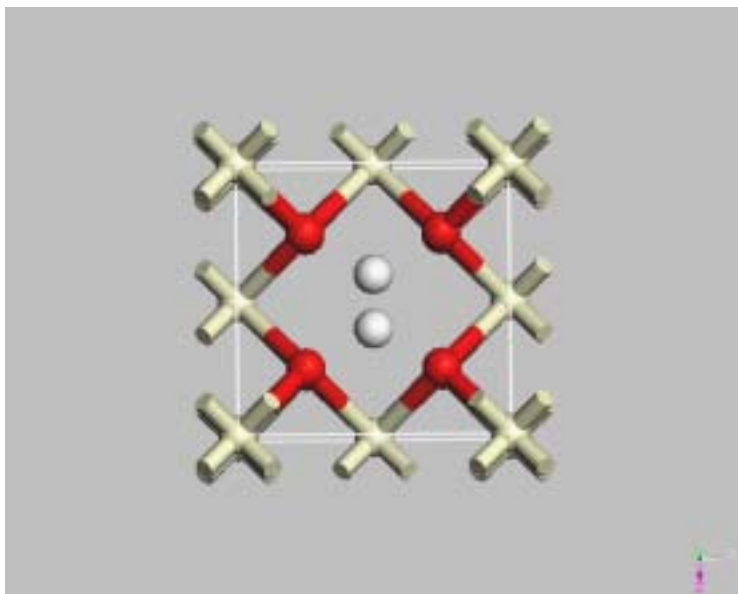
Conditions	dist(CeO)	Occ (O)	χ^2
25°C Air reference	2.342Å	1.00	0.6
800 °C H ₂ /He	2.409	0.89	0.3
800 °C He only	2.368	1.00	0.3
800 °C CO/He	2.410	0.93	2.7

On reduction at 800 °C

Distance of CeO increases 0.04Å in H₂/CO

Occupancy of O changes 0.1 in “reduced” CeO_x

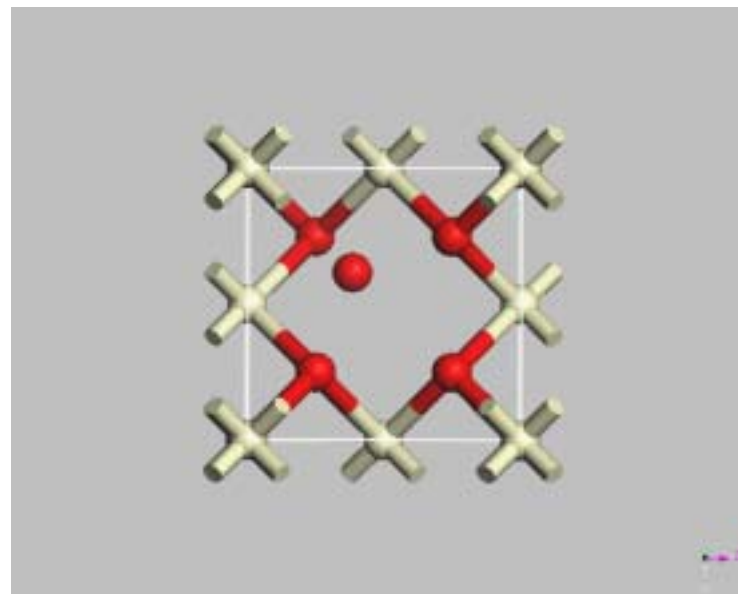
Models in Cavity



H₂

Stable minima in DFT

Density in $\Delta\rho$ map

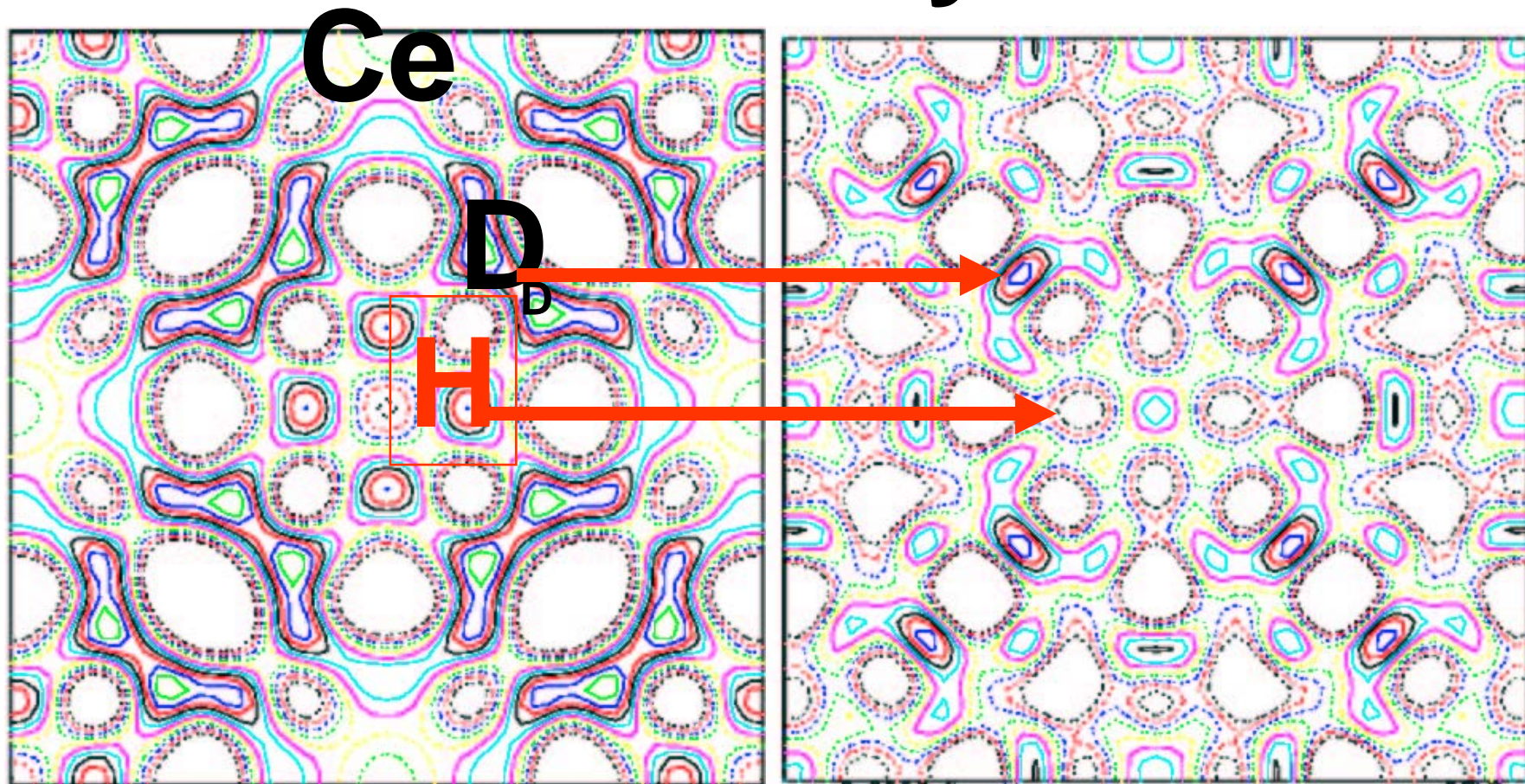


Egami Frenkel Defect

DFT move back to normal
site

Density in $\Delta\rho$ map

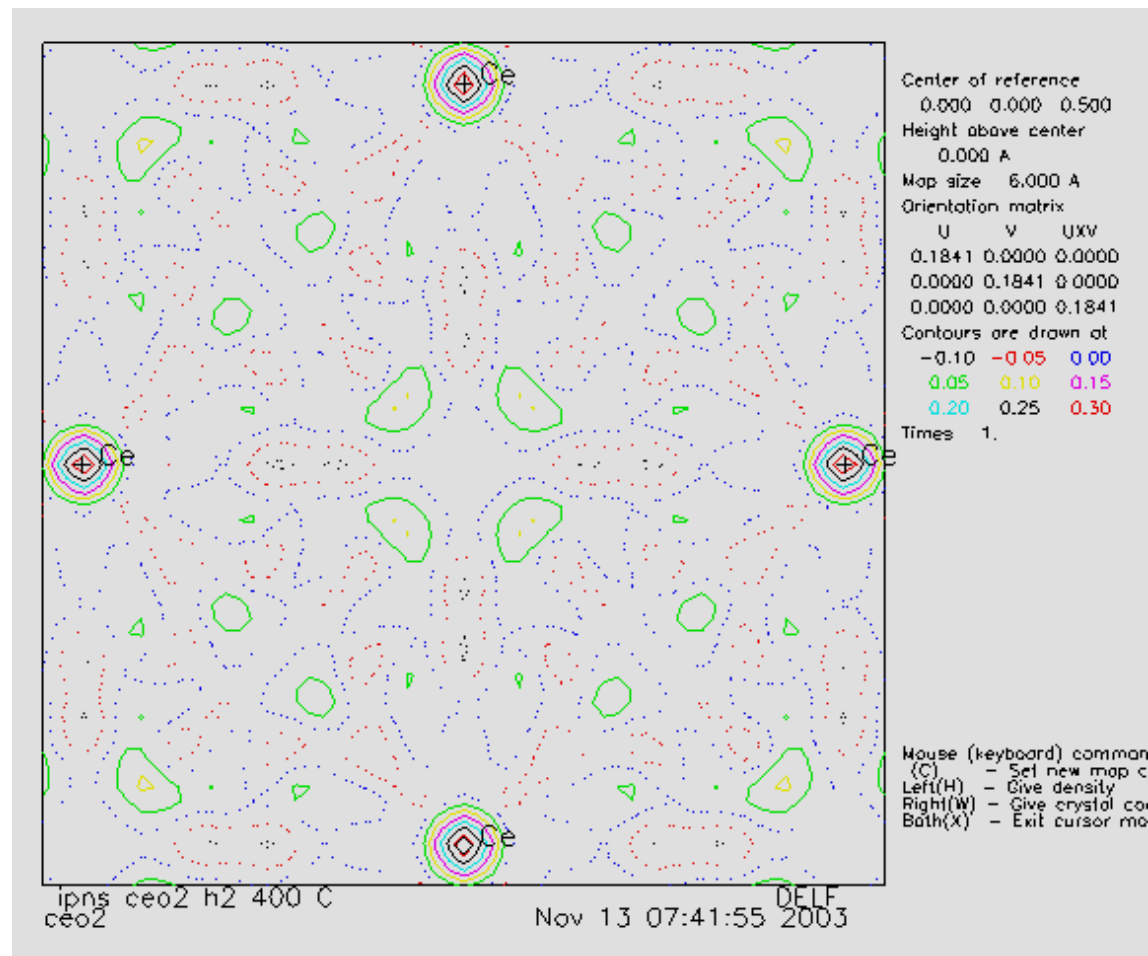
Electron Density in Central Cavity



H₂/He Flow 800 C

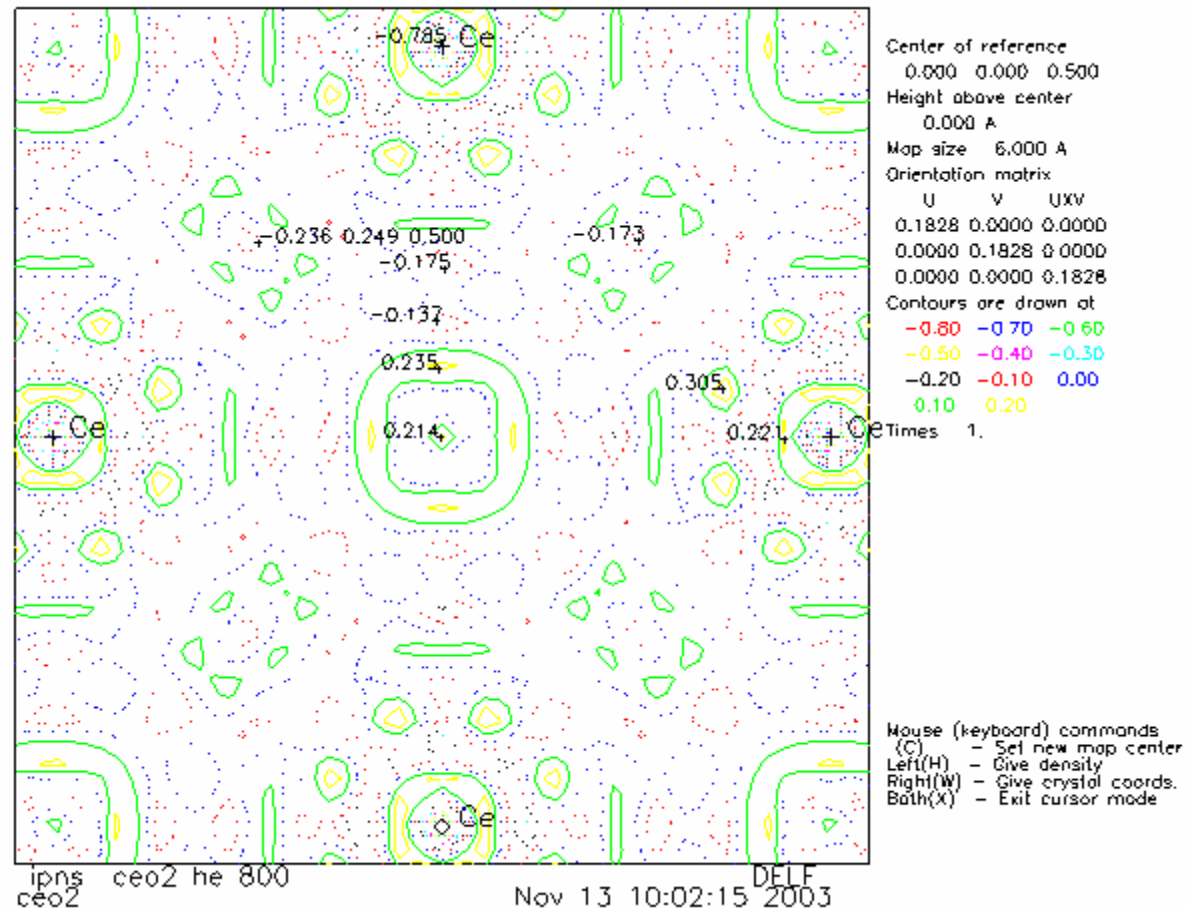
He only Flow 800°C

Neutron diffraction from bulk ceria in H₂ at 400C



Rwp= .16 RFsq= .13 a=5.4327 occ=.956

Neutron diffraction from bulk ceria in H₂ at 400C



$R_{wp}=0.14$ $R_{fsq}=0.15$ $a=5.4711$ $occ=.925$

Vacancies in Ca doped ceria

Ce:Ca ratio	Lattice Constant	O Occupancy in lattice
1:0	5.420	1.02
9:1	5.416	0.94
8:2	5.416	0.94
2:1	5.394	0.86*

- 0.86 implies $\text{Ce}_{0.66}\text{Ca}_{0.33}\text{O}_{1.72}$ instead of ideal $\text{Ce}_{0.66}\text{Ca}_{0.33}\text{O}_2$
- Rodriguez, et al. J. Phys. Chem. (2003) **119**, 5659-5669

Conclusions

- In situ time resolved powder diffraction provides:
 - Useful information of intermediate phases
 - Faster detector would help
 - Structural information during transformation
 - Complexity of refinement restricts certainty of model
 - Useful trends of transformation can be obtained

Acknowledgements

Clare Grey

Chemistry, SUNY-Stony Brook

Jae Kim

Chemistry, BNL

M. Fernandez-Garcia

CSIC, Madrid, Spain

Simon Billinge

Michigan State University

Xiangyun Qiu

S. Smart

SEPD IPNS ANL

DOE(Div. of Materials and Chemical Sciences) NSLS and APS

Chem. Dept :DOE contract DE-AC02-98CH10886